

Abstract Submitted
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Atomic Force Microscopy Education NANCY BURNHAM, ANDREW PIC, VALERIE MOORE, Worcester Polytechnic Institute — Atomic force microscopy is a crucial part of nanoscience. Despite the simplicity of its design, a simple cantilever with a sharp tip, learning and teaching AFM can be difficult. Five levels of AFM education were identified from existing education infrastructure: demonstrations, single or several laboratories within another course, term or semester based courses devoted to AFM, personalized hands-on instruction, and short courses. Information was gathered from a survey as well as interviews given to figures in AFM education. Advice, general practices, and a list of resources were compiled into a website, presentation, a project report, which was in turn accepted as a chapter in a book [1]. These are intended to become a resource to help educators approach and design their own AFM educational experience. [1] A.C. Pic, V.A. Moore, N.A. Burnham, Atomic Force Microscopy Education, in *Global Perspectives of Nanoscience and Engineering Education*, pp. 131-169 (2016), Eds. K. Winkelmann and B. Bhushan

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